

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09842596	SHANHAVEERAIAH ET AL.
	Examiner Nano, Sargon N	Art Unit 2157

Notes	Date	Examiner
EAST, Consulted with Primary Robert Harrell, Consulted with Primary Paul Myers	8/23/06 and 8/25/06	SN
U.S. Patent and Trademark Office		Part of Paper No.: 20060829

<b>Interference Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Class	SubClass	Date	Examiner
709	220, 222, 207	08/29/2006	

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Class	SubClass	Date	Examiner
709	220-224,227	08/29/2006	SN

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